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Dr. Cemal Basaran is a Professor and the Director of Electronic Packaging Laboratory at the State University of New York at Buffalo.

He specializes in computational and experimental reliability of power and nano electronics packaging. He has authored more than 125 peer reviewed archival journal publications and many book chapters in the fields of damage mechanics of electronics packaging. His research includes but not limited to graphene, carbon nano tube based power and nano electronics, electromigration, thermomigration, thermo-electro-mechanical induced fatigue, and nano-resolution high sensitivity moiré interferometry. Some of his awards include 1997 US Navy ONR Young Investigator Award, and 2011 ASME EEPD Excellence in Mechanics Award. He is a Fellow of the ASME. He has served and continues to serve on editorial board of eleven peer reviewed international journals, including IEEE Trans. on Advanced Packaging, IEEE Components, Packaging and Manufacturing Tech , ASME Journal of Electronic Packaging, ASCE Journal of Nanomechanics and Micromechanics, International Journal of Materials and Structural Integrity, Journal of Recent Patents on Electrical Engineering as well as numerous other journals. He has been the primary dissertation advisor to 21 PhD students in the last 17 years.

His research has been funded by NSF, ONR, DoD, State of New York, and many industrial sponsors including but not limited to Northrop Grumman, Raytheon, Delphi, Intel, DuPont, Texas Instruments and many others.

He serves as advisor to many national and international research funding agencies around the globe.